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Application/Control No.	Applicant(s)/Patent under Reexamination
10/642,896	TAKANO ET AL.
Examiner	Art Unit

Frank Duong

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SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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Interference Search (see printout)		10/29/2007	FD	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated EAST Search (see printout)	10/29/2007	FD		
Updated Inventorship (see printout)	10/29/2007	FD		
Updated IEEE/Internet Search	10/29/2007	FD		
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